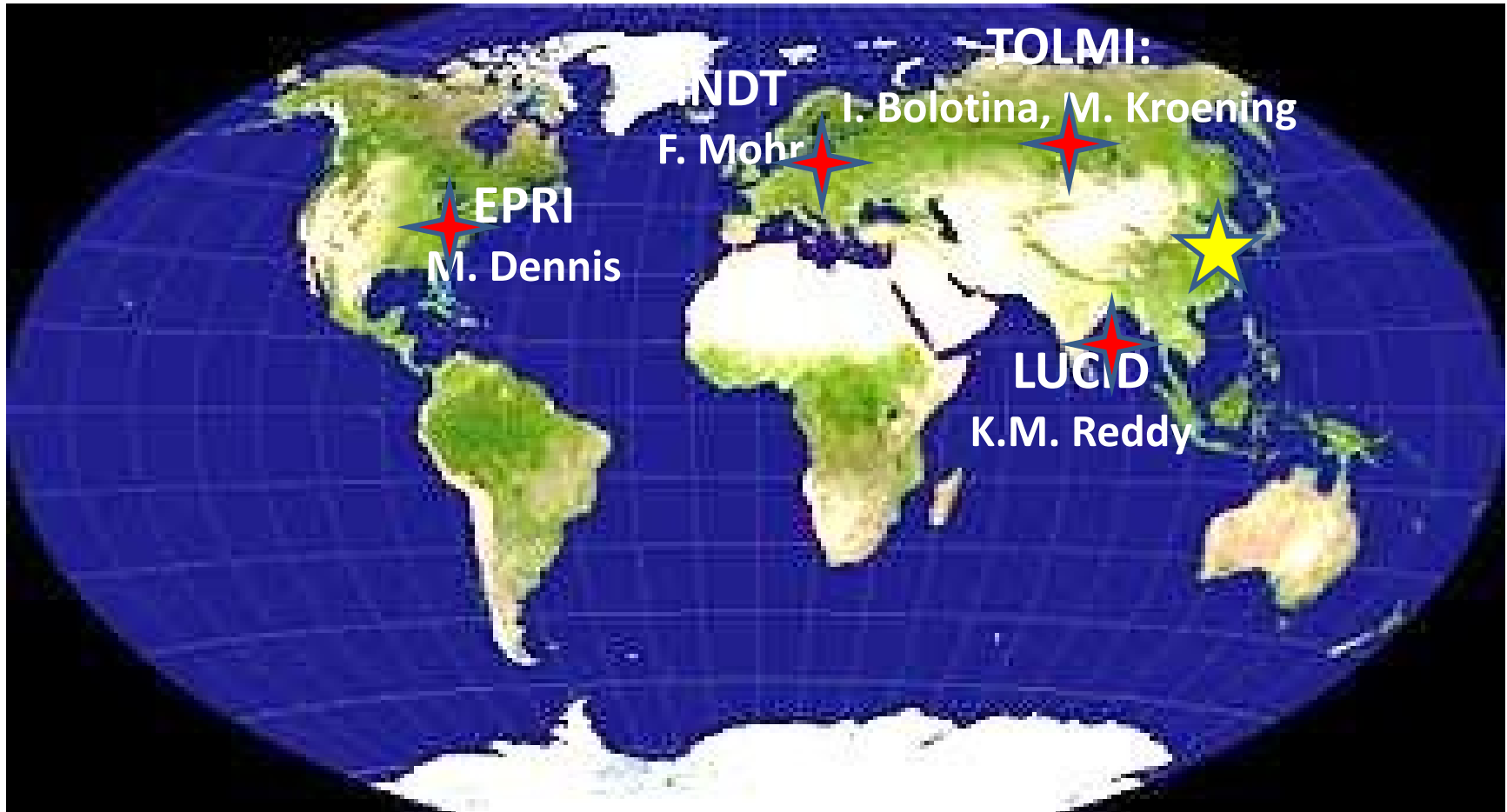


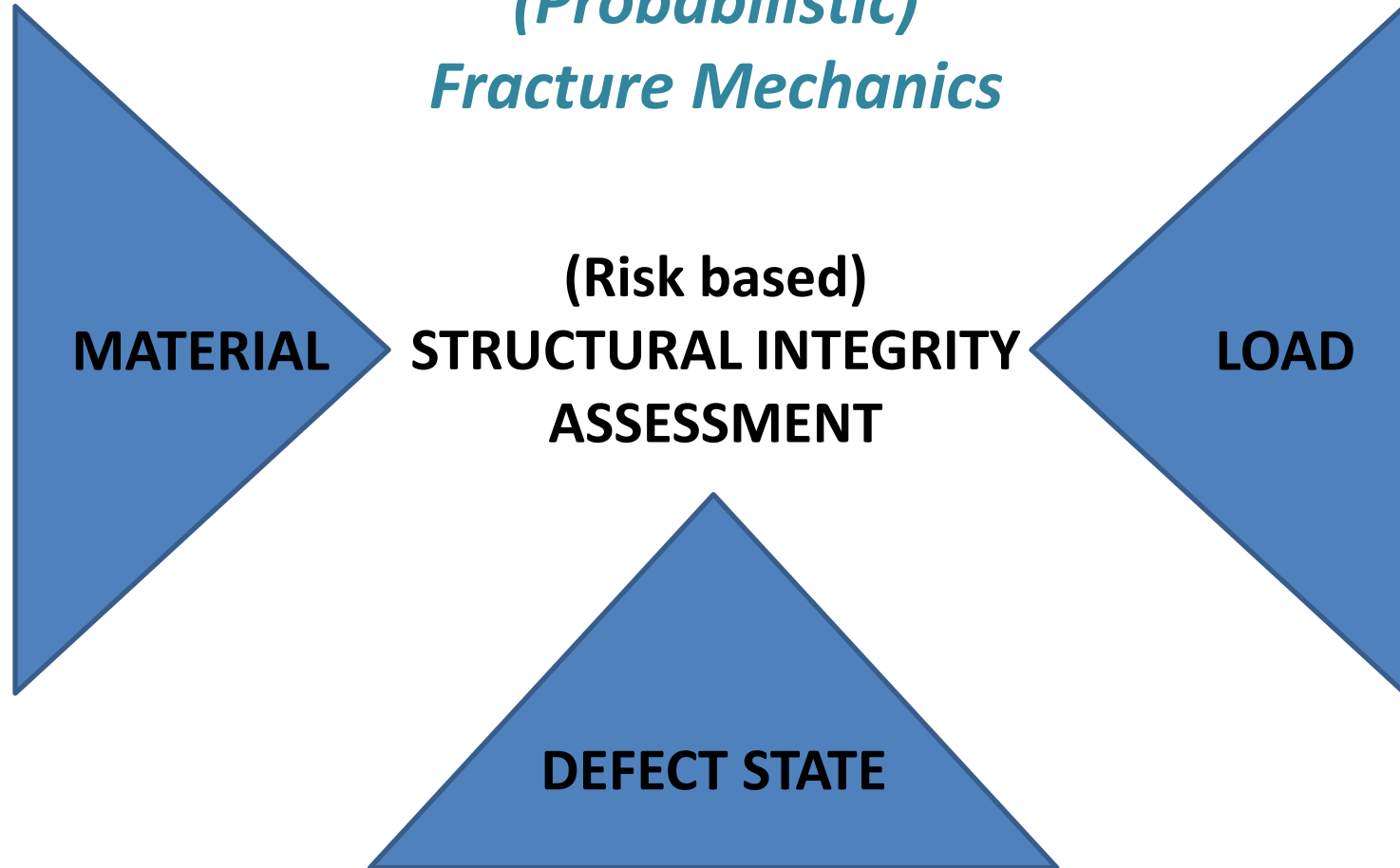
Advanced UT Systems

Michael Kröning

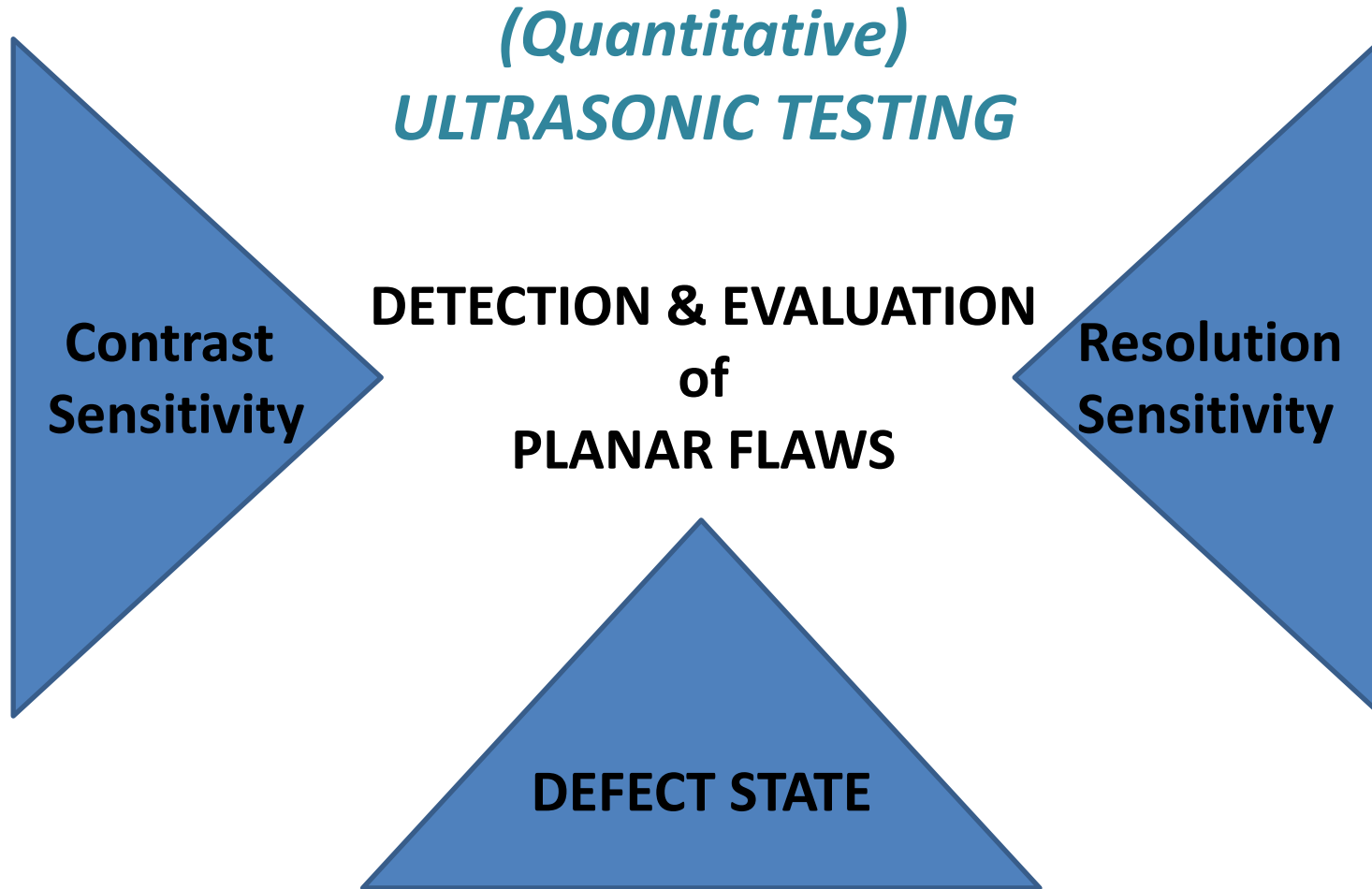


MOTIVATION

*(Probabilistic)
Fracture Mechanics*

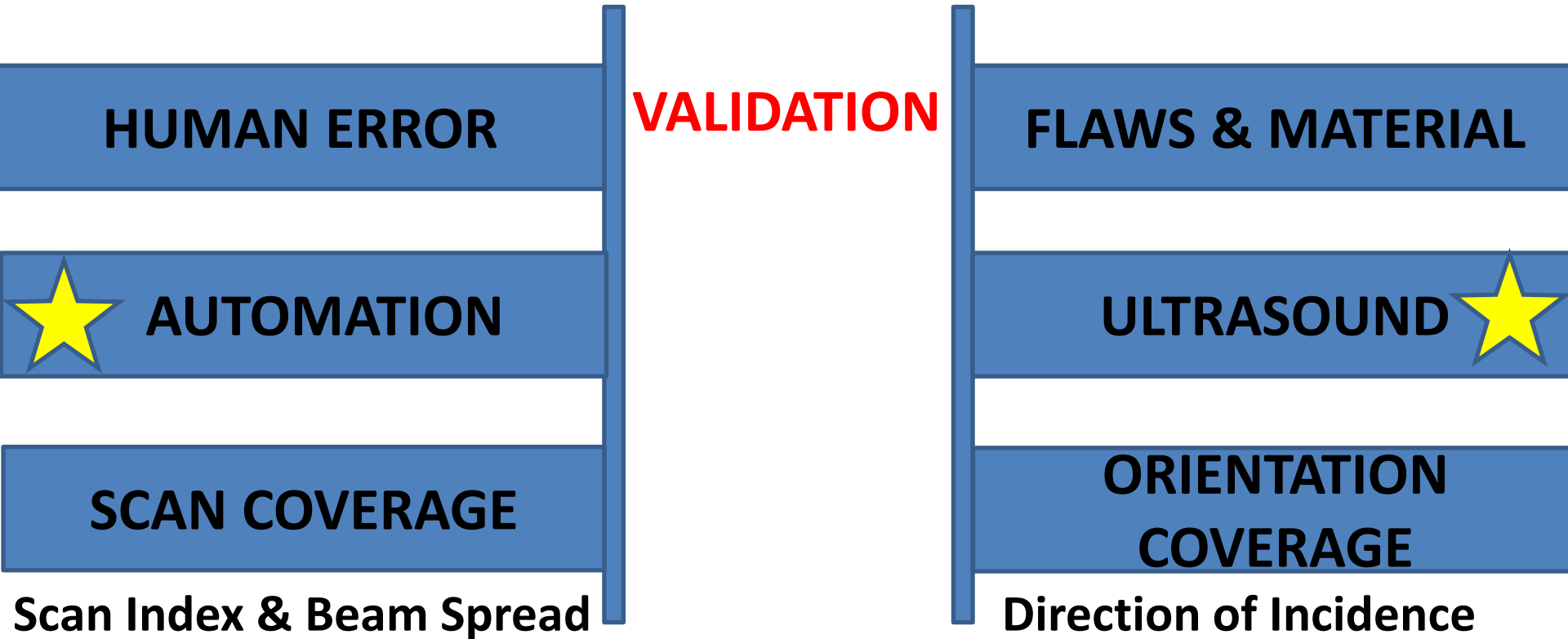


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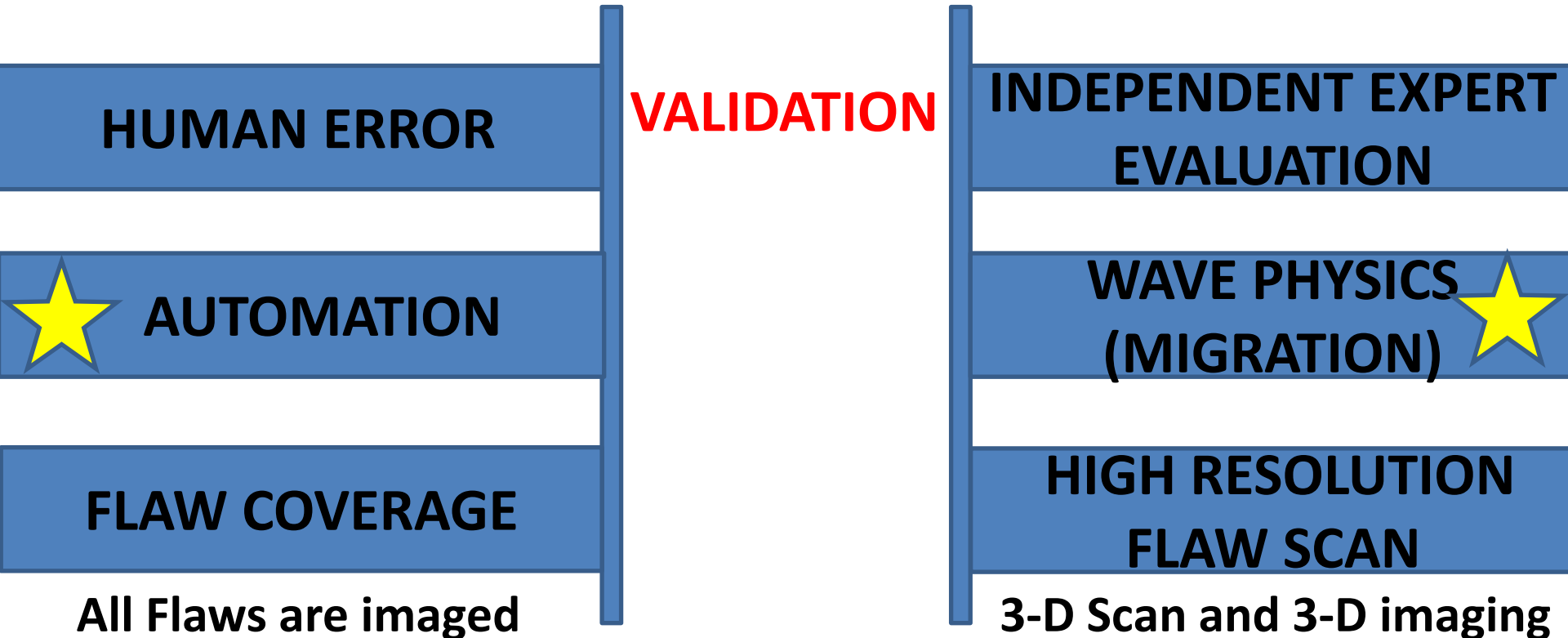
PROBABILITY OF DETECTION

$$\text{PoD (planar flaws)} = f(\text{Performance}) \times f(\text{Contrast})$$



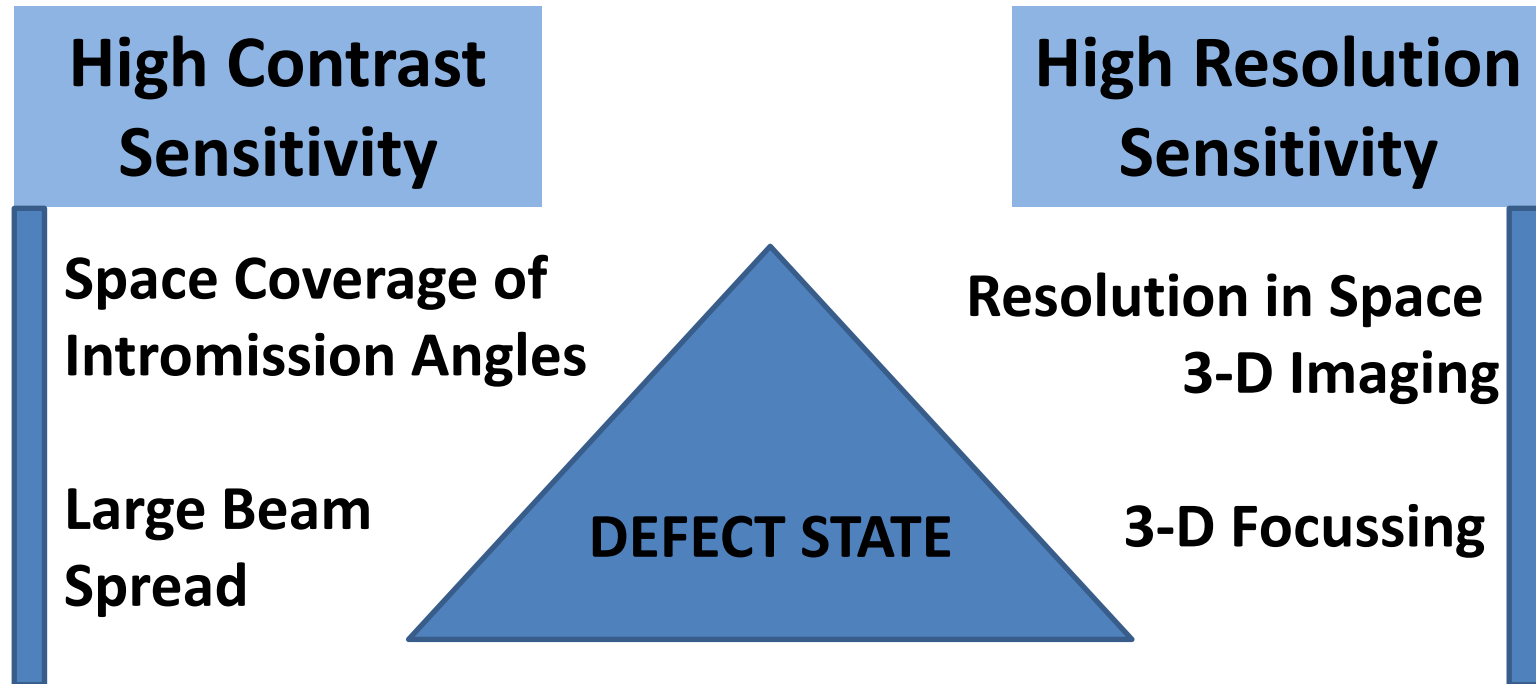
FLAW EVALUATION

**There are many experts and procedures
We rely on ultrasonic high resolution imaging**



CHALLENGE

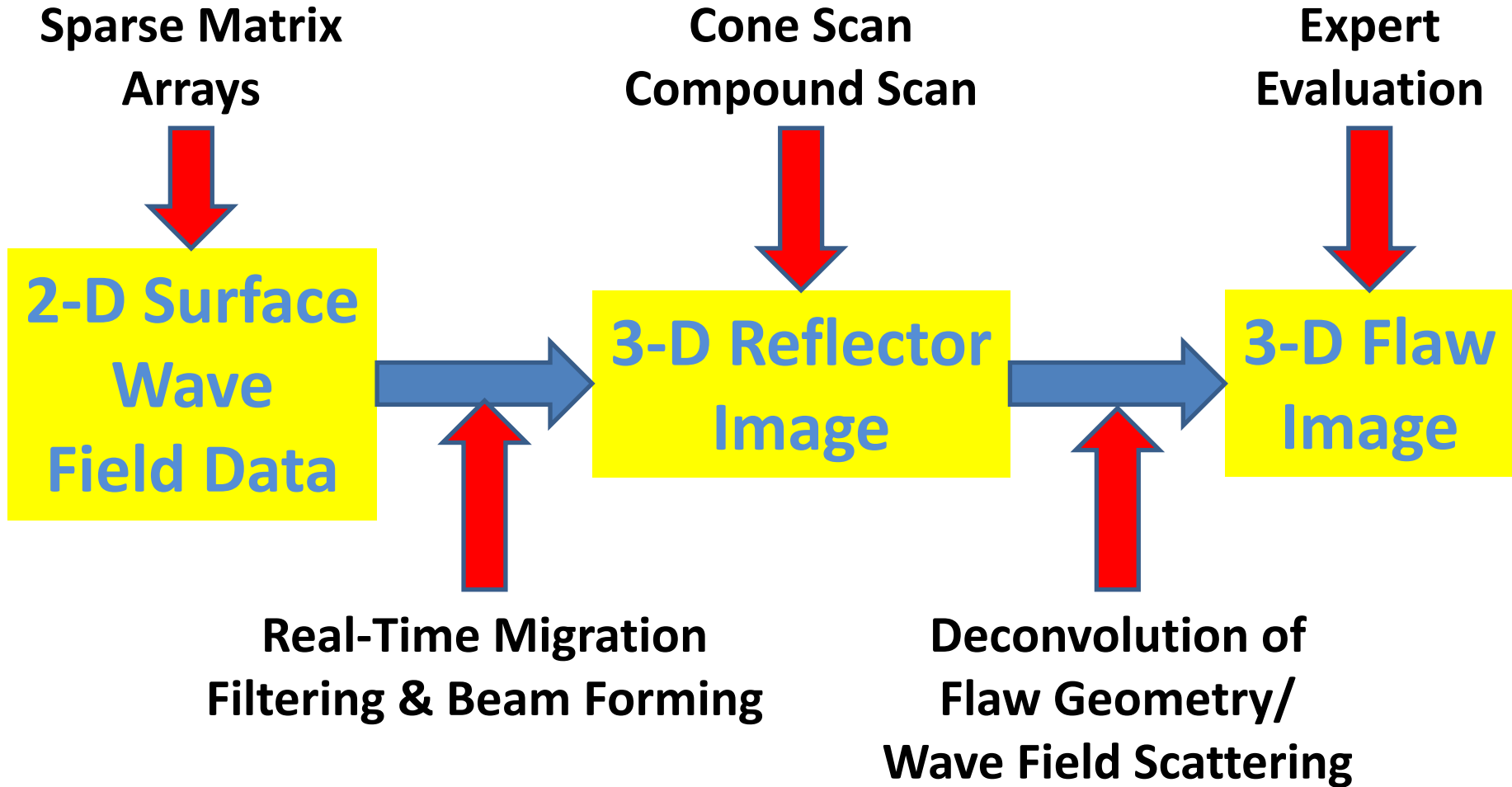
Contradicting Requirements

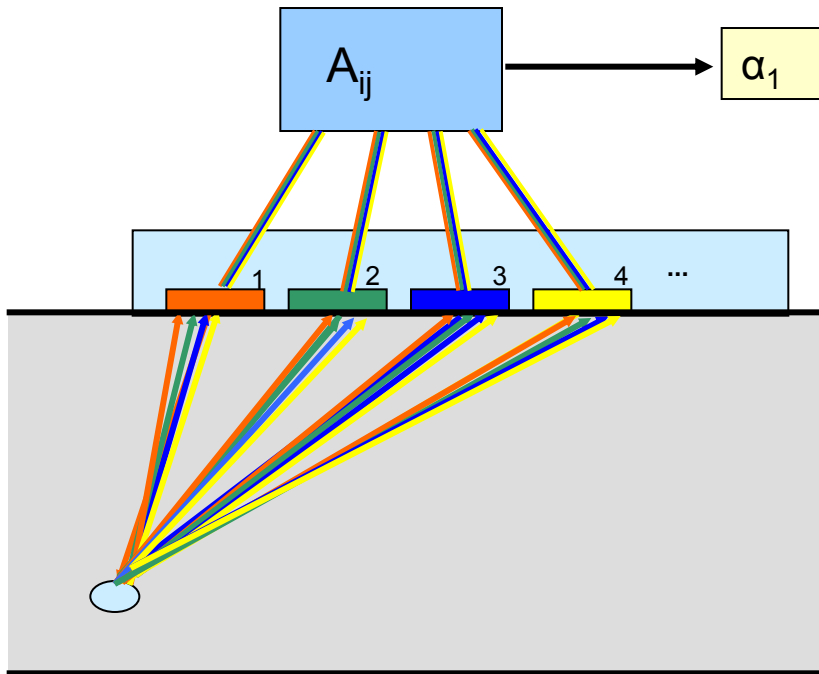


(Quantitative)
ULTRASONIC TESTING

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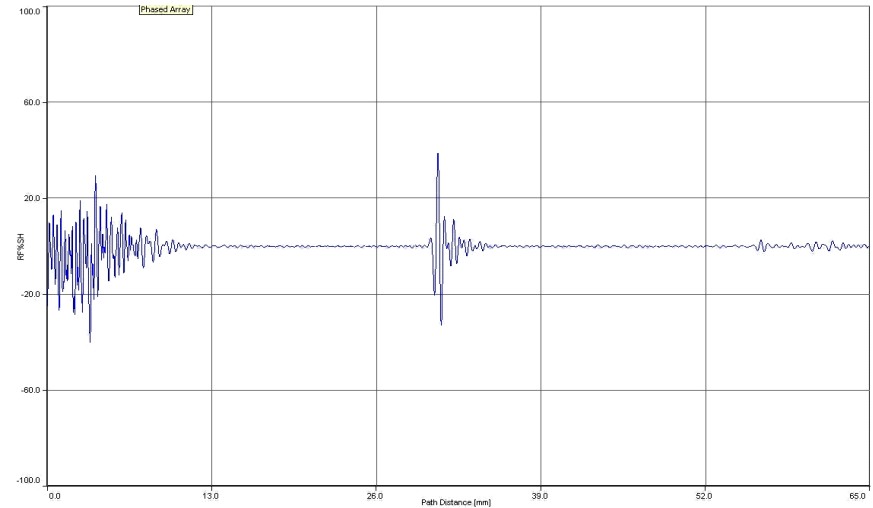
R&D OBJECTIVES





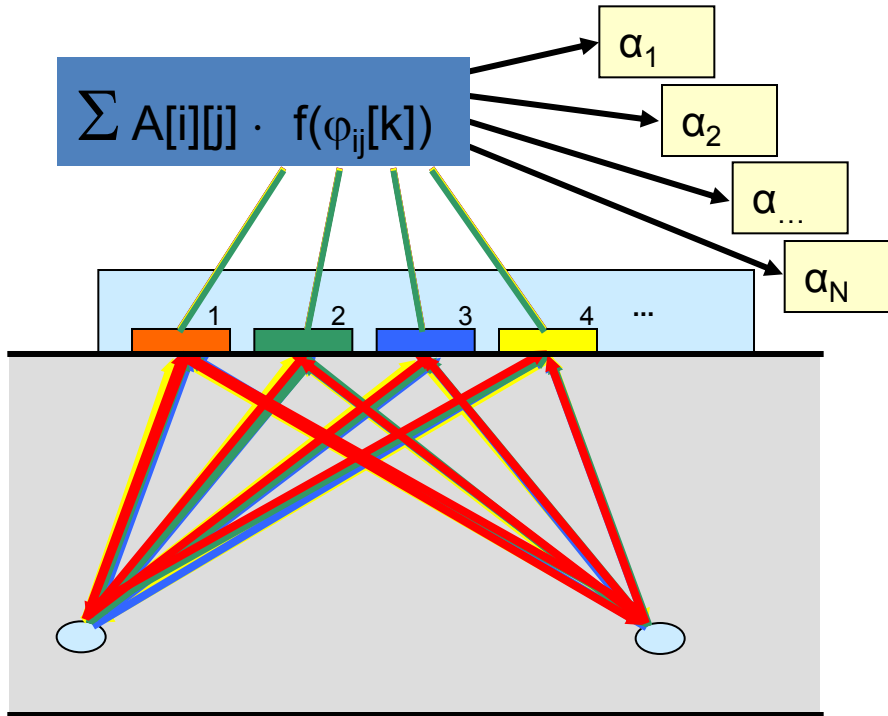
A-SCAN: $A_{\alpha}(t)$

α – Beam Angle



Signal Generation Using Conventional PA

$\varphi_{ij}[k]$ – corresponding phase delay for beam angle α



Information Matrix A_{ij}

i – transmitter number

j – receiver number

A_{11}	A_{12}	A_{13}	A_{14}
A_{21}	A_{22}	A_{23}	A_{24}
A_{31}	A_{32}	A_{33}	A_{34}
A_{41}	A_{42}	A_{43}	A_{44}

Notation: $m \times n$

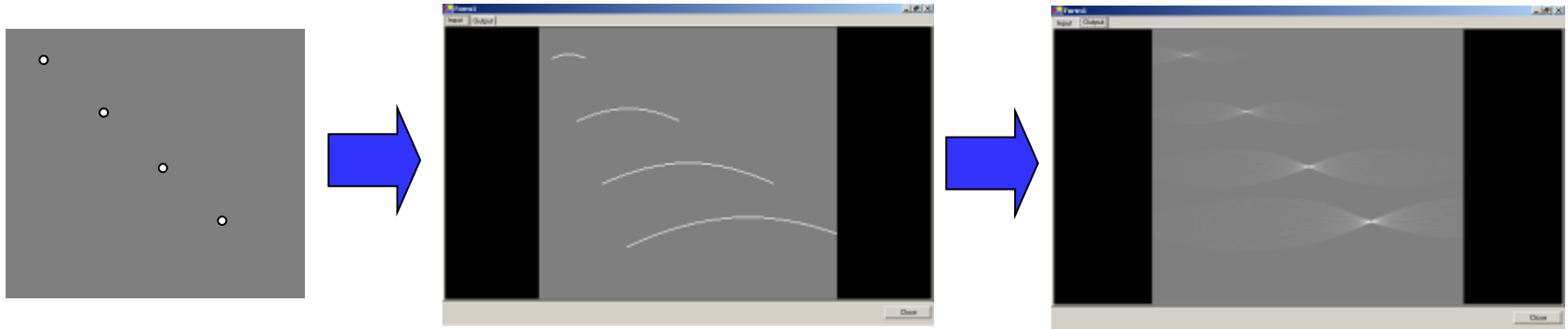
m – number of active transmitters

n – number of active receivers

Sampling PA Signal Generation

Synthetic Aperture - SAFT

SAFT Reconstruction



A_{11}	A_{12}	A_{13}	A_{14}
A_{21}	A_{22}	A_{23}	A_{24}
A_{31}	A_{32}	A_{33}	A_{34}
A_{41}	A_{42}	A_{43}	A_{44}

ACOUSTIC MIGRATION (As Realized for NDT Applications)

Kirchhoff Ansatz:

$$C(t) = G \sum_i w_i A_i(t - t_i)$$

x_i : element position

z_j : depth position

$C(t)$: computed

RF echo return

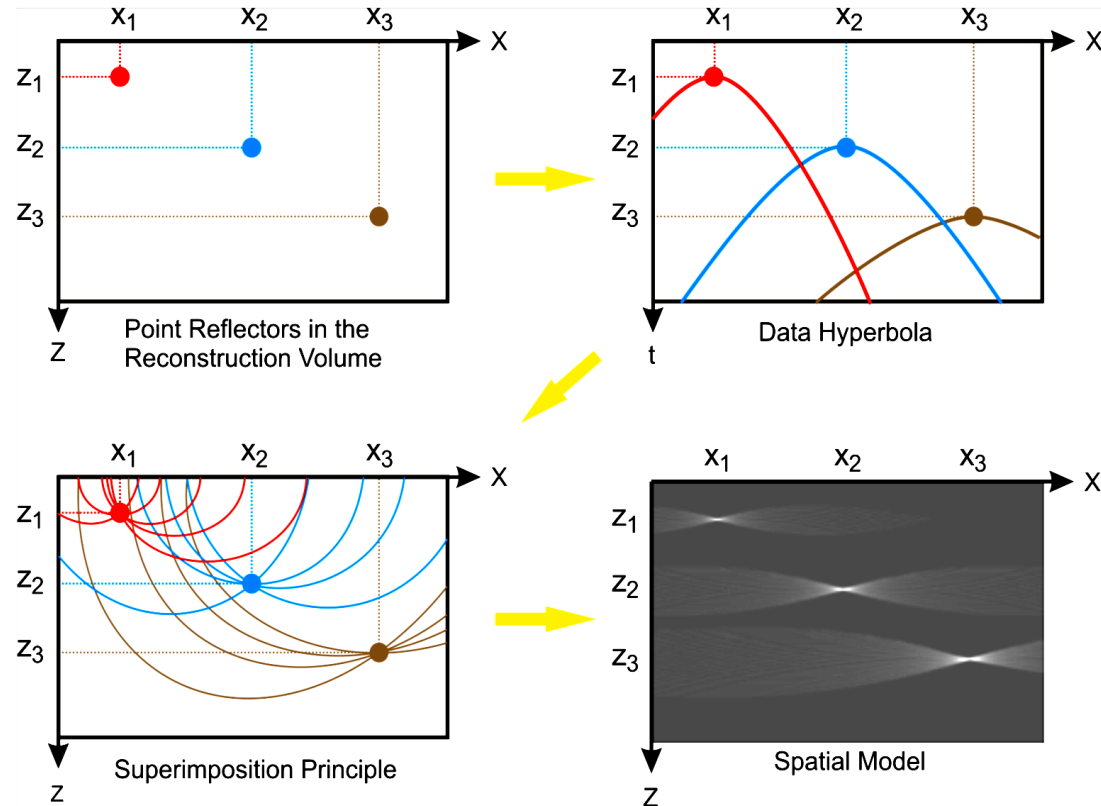
$A_i(t)$: returned signal

w_i : weight assigned

to $A_i(t)$

t_i : time delay for element i .

G : goodness of fit enforcement (SynFoc© by LucidSoft)



THAT'S WHAT WE WANT!**Resolution Sensitivity:**

- ➔ depends on the element aperture in the near field of the array aperture (synthetic focusing)
- ➔ is close to the Rayleigh limit for $\lambda/2$ element apertures
- ➔ can be increased by super resolution techniques

Contrast Sensitivity:

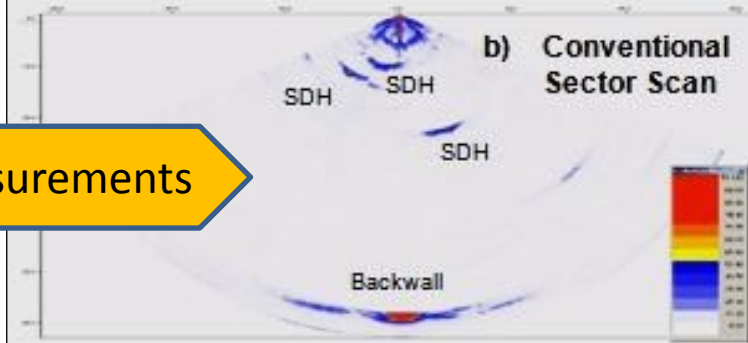
- ➔ Matrix arrays:
sensitive to all space directions within the chosen cone angle
- ➔ Linear Arrays:
covers all angle of incidence of the chosen sector scan angle including angles beyond the first critical angle (shear mode)

ACOUSTIC MIGRATION
(As Realized for NDT Applications)

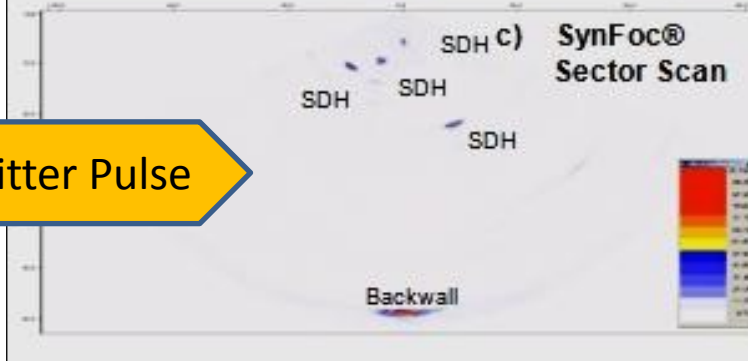
71 Measurements



71 Measurements



1 Transmitter Pulse



Experimental Data:

Test Specimen: Steel 55 mm thick
SDH \varnothing : 1mm
Linear Array Transducer:
F = 5 MHz; 16 Elements



Partial View of Test Specimen with Transducer

Transducer

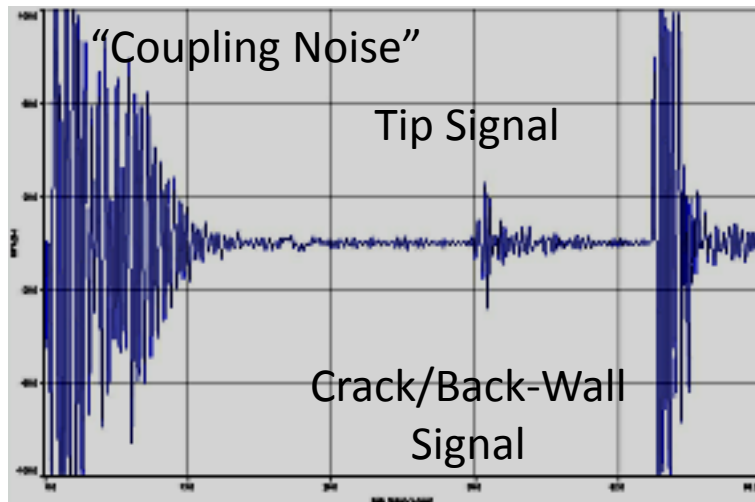
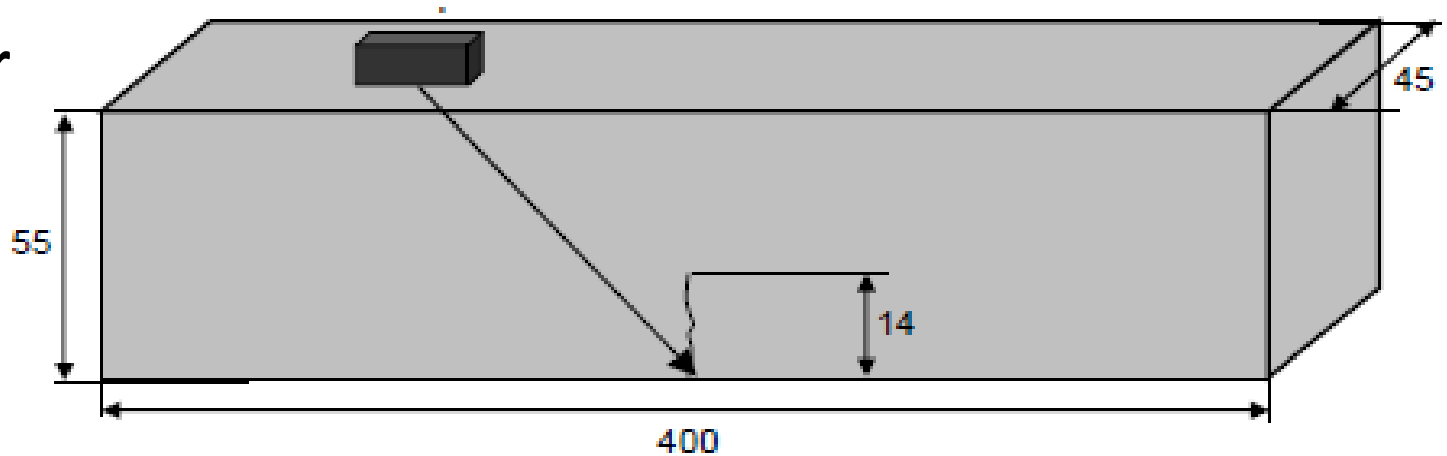
Linear Array

64 elements

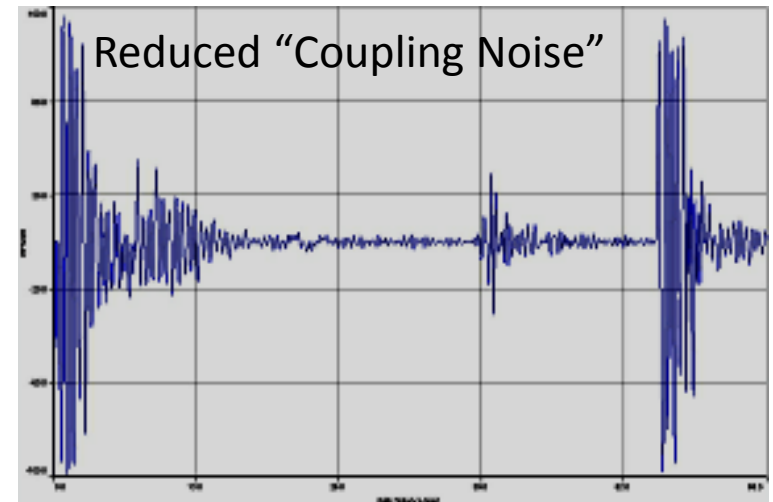
16 used

f = 5MHz

Longitudinal

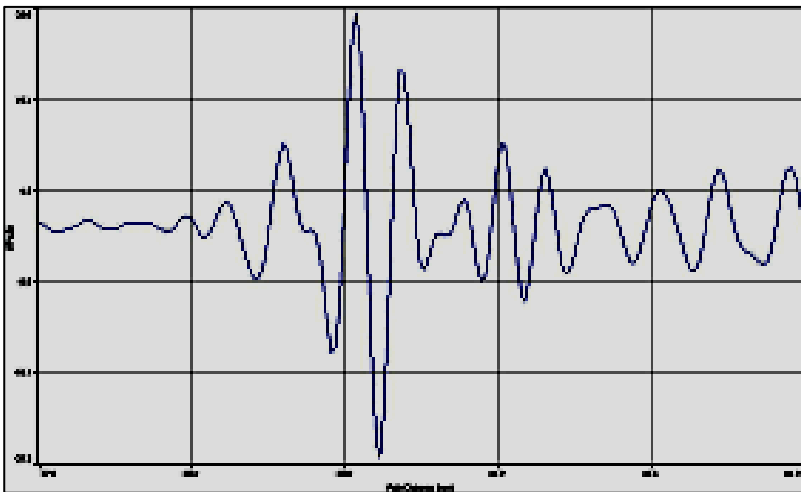


Phased Array Mode 45° long.

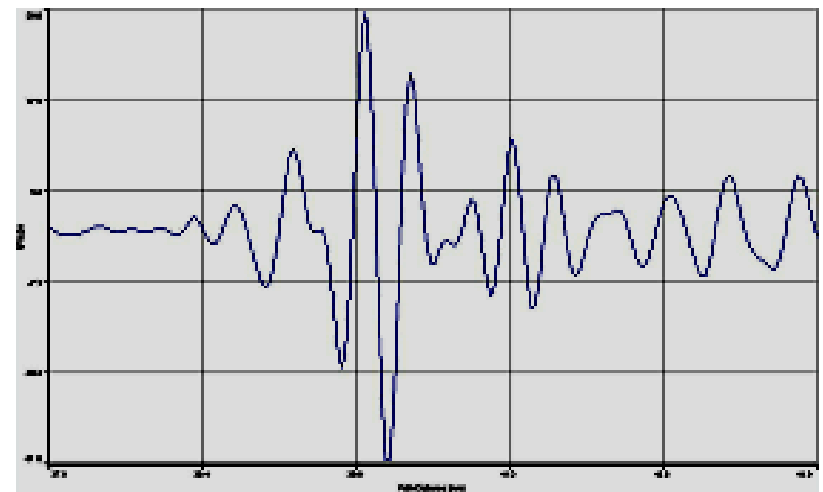


Migration Mode
Reconstructed A-Scan 45° long.

Zoomed Crack Tip Signals



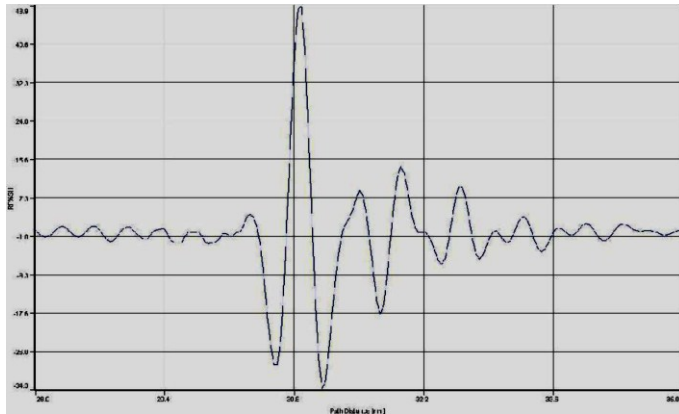
Phased Array Mode



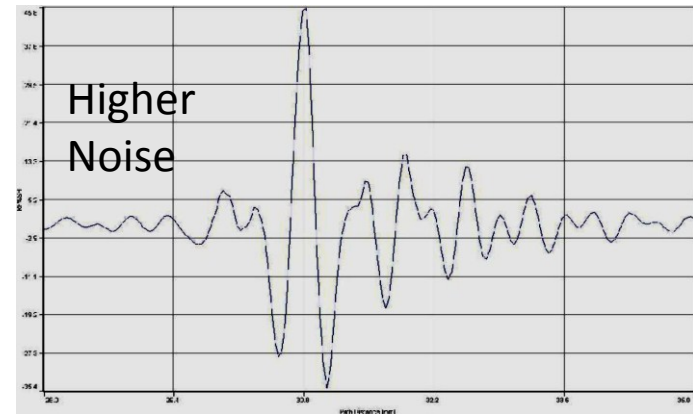
Migration Mode

REAL-TIME MIGRATION

All 16 elements used as transmitter in sampling mode by multiplexing



Only 1 element used as transmitter in 1 transducer position



All 16 elements used as receiver simultaneously in parallel mode

Transducer:
5 MHz Linear Array
64 elements
with 16 used

POINT REFLECTOR SIGNALS
(Reconstructed A-Scans 45° long)

TECHNICAL CHALLENGES

(we are working on it)

LARGE ARRAY APERTURES FOR LONG DISTANCE FOCUSING

- Reasonably low number of array elements
 - SPARSE APERTURES

$\lambda/2$ ARRAY ELEMENTS FOR HIGH RESOLUTION SENSITIVITY

- Reasonably efficient array elements
 - STACKED ELEMENTS (3 LAYERS)

SPARSE APERTURES

An example for consideration

Phased Array Transducer:

8x8 (16x16) Matrix Array with 64 (256) $\lambda/2$ elements

f = 3 MHz

Array Aperture: (8x8) (16x16)mm²

in compliance with Sampling Theorem

➤ **Near Field Distance: ~ 7.5 (30)mm**

Migration Array Transducer

with reasonably low number of elements

and large near field distance:

8x8 $\lambda/2$ elements with an aperture of (32x32)mm²

in sparse arrangement (Distribution Factor 4)

➤ **Near Field Distance: ~ 130 mm**

TRANSDUCER:

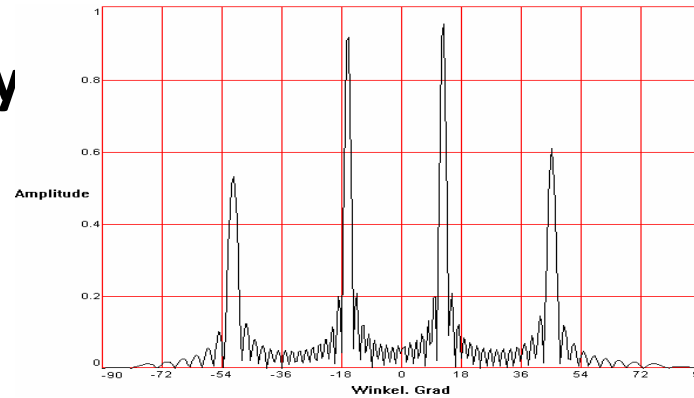
64 element linear array

16 elements used

$f = 5 \text{ MHz}$

Distribution Factor: 4

(Element Skip: 2λ)

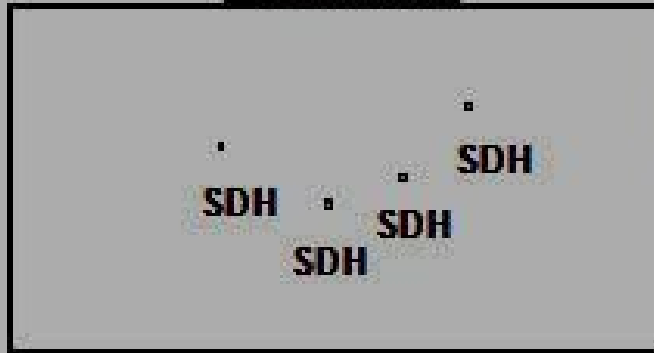


BEAM PROFILE

Phased Array mode

Phase control: 0°

PA
Transducer



Test specimen



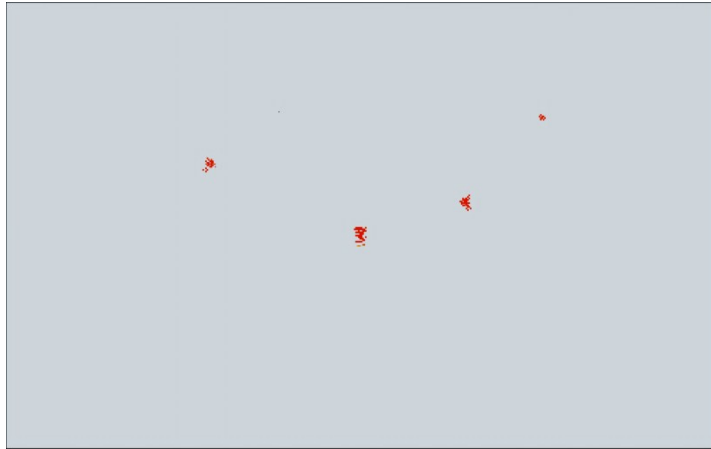
Phased Array sector scan



Migration image

SPARSE ARRAY SECTOR SCANS

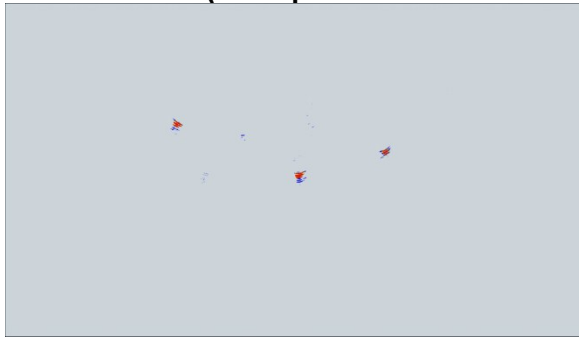
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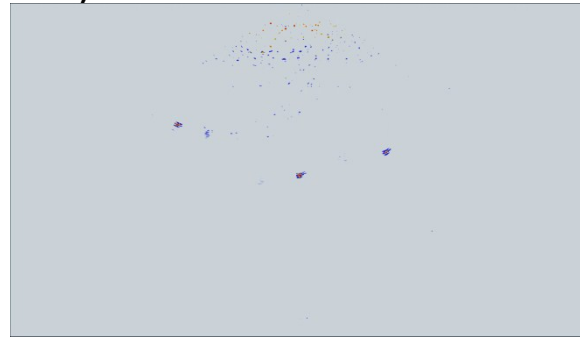
Migration by 64 elements
(full possible information)



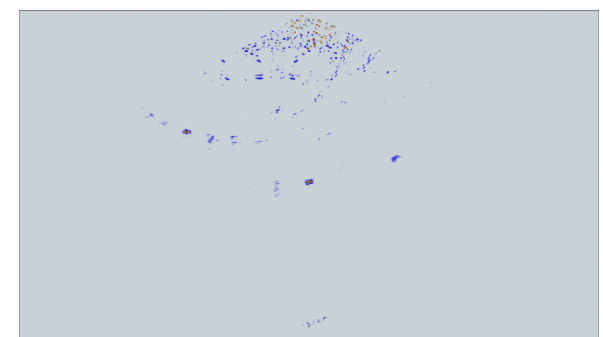
Migration by 6 elements
stochastic distribution



Migration by 16 elements
homogeneous, DF = 4



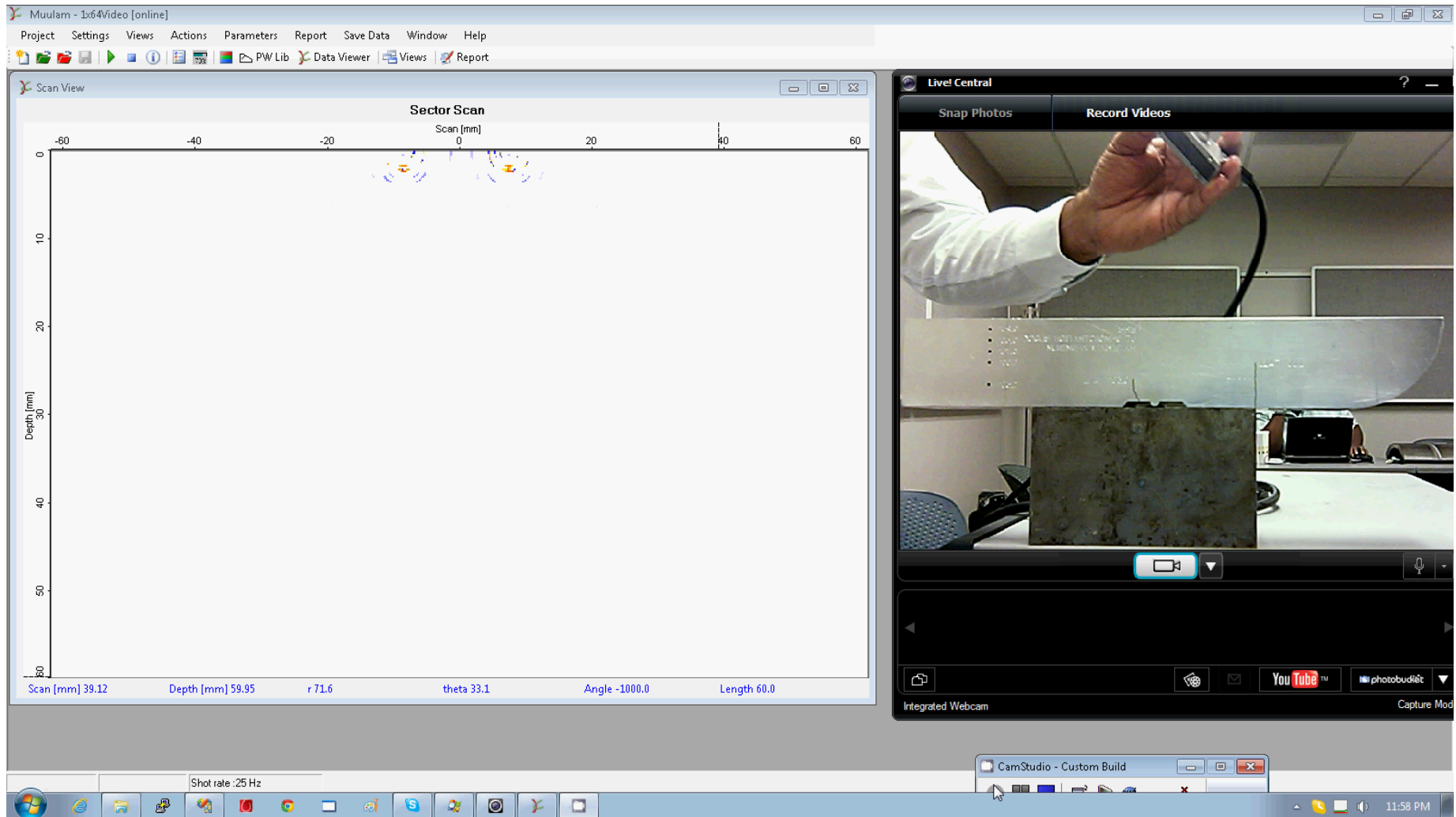
Migration by 8 elements
homogeneous, DF = 8



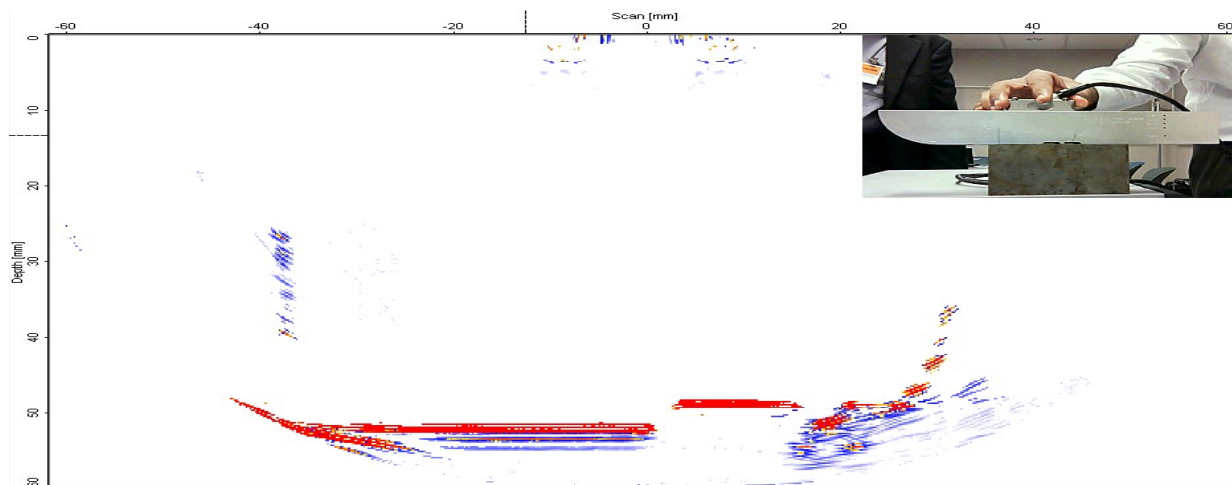
Migration by 6 elements
homogeneous, DF = 10

SPARSING LIMITS

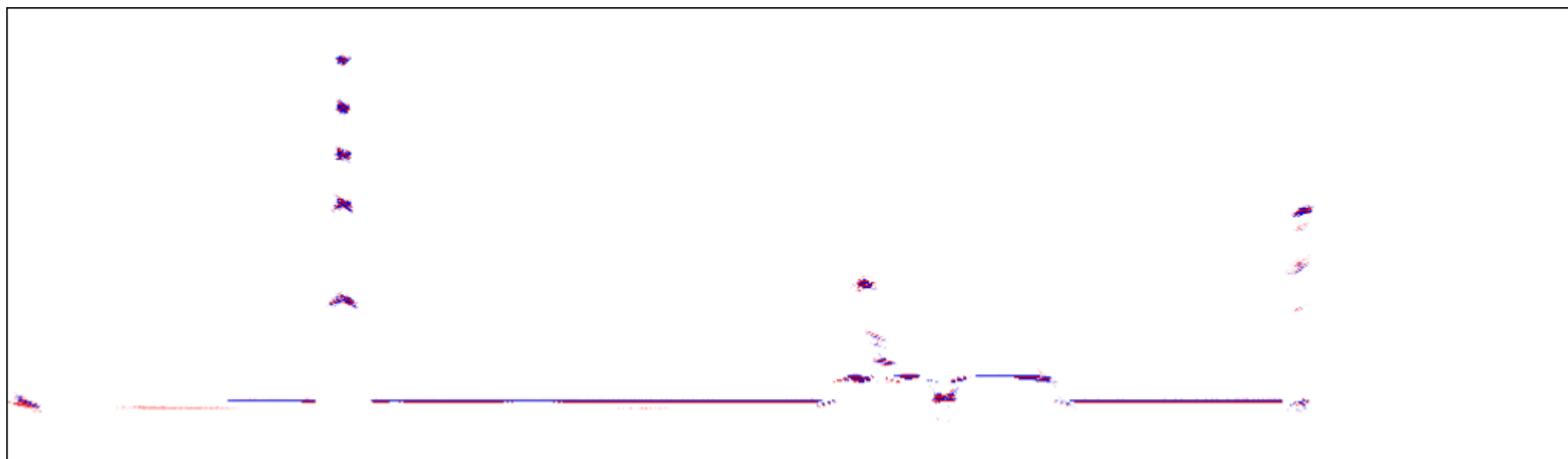
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The screenshot displays a software interface for ultrasonic testing. The main window is titled "Scan View" and shows a "Sector Scan" graph. The x-axis is labeled "Scan [mm]" and ranges from -60 to 60. The y-axis is labeled "Depth [mm]" and ranges from 0 to 60. The graph shows a scan profile with a peak at approximately 0 mm scan and 10 mm depth. Below the graph, the following parameters are displayed: Scan [mm] 39.12, Depth [mm] 59.95, r 71.6, theta 33.1, Angle -1000.0, and Length 60.0. The interface also includes a menu bar with options like Project, Settings, Views, Actions, Parameters, Report, Save Data, Window, and Help. A toolbar contains icons for various functions. In the bottom right corner, there is a "Live! Central" window showing a video feed of a person in a white lab coat holding a probe over a metal block. The video feed includes controls for "Snap Photos" and "Record Videos". The Windows taskbar at the bottom shows the system tray with the time 11:58 PM and a "CamStudio - Custom Build" window.

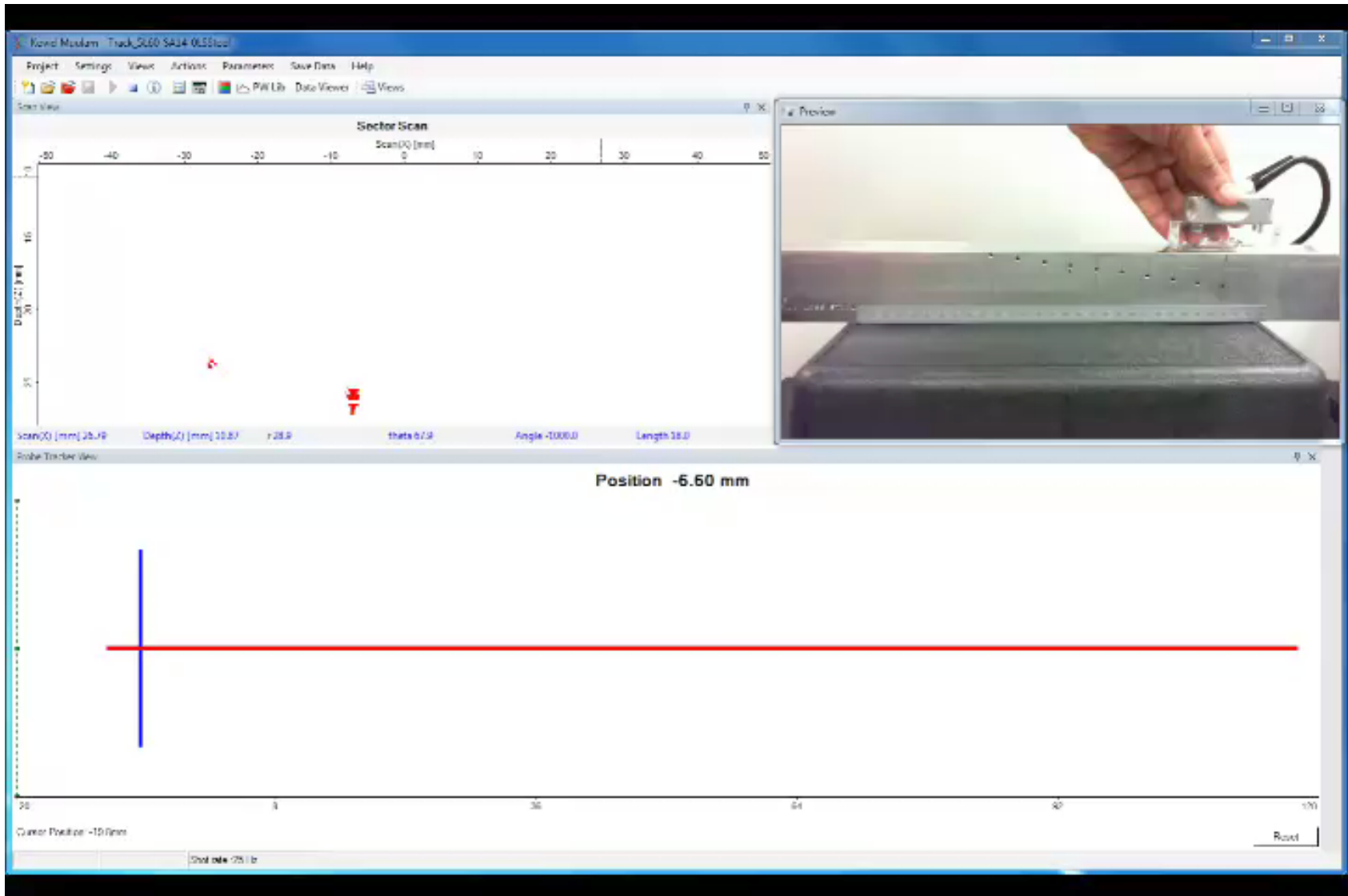


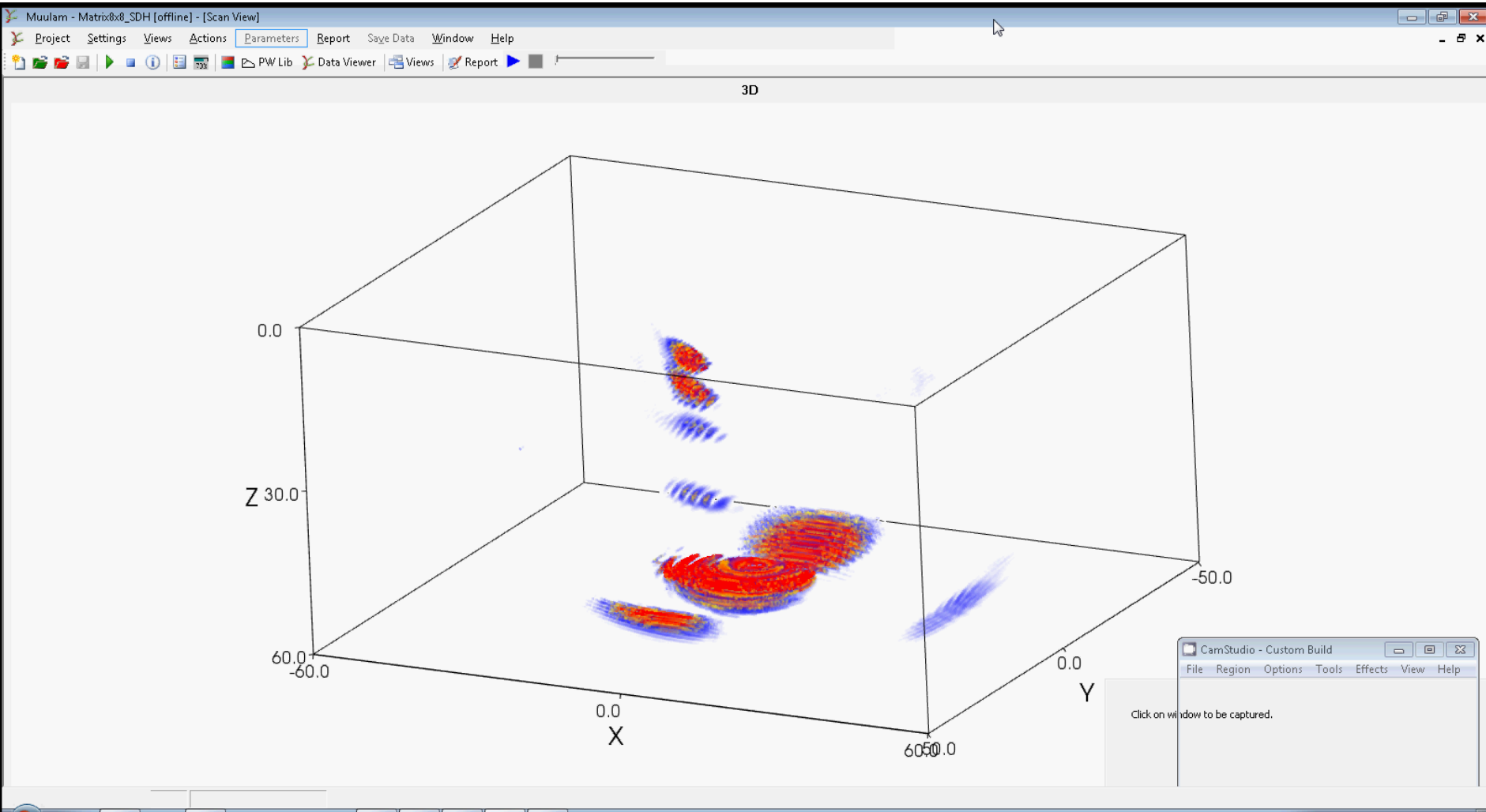
Sector scan reconstruction of Alu block with side drilled hole



B-Scan reconstruction of Aluminium block

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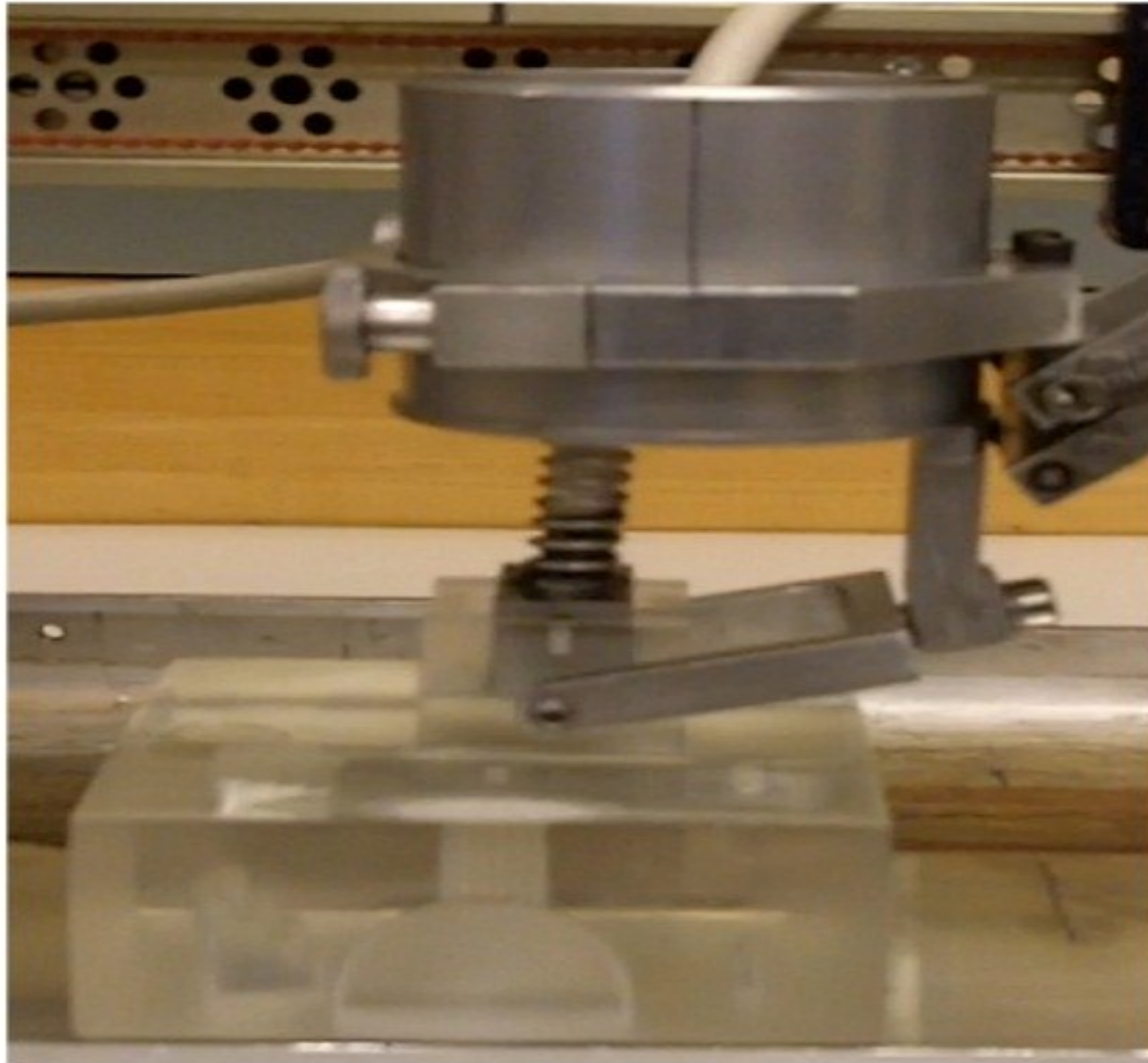


GRINM

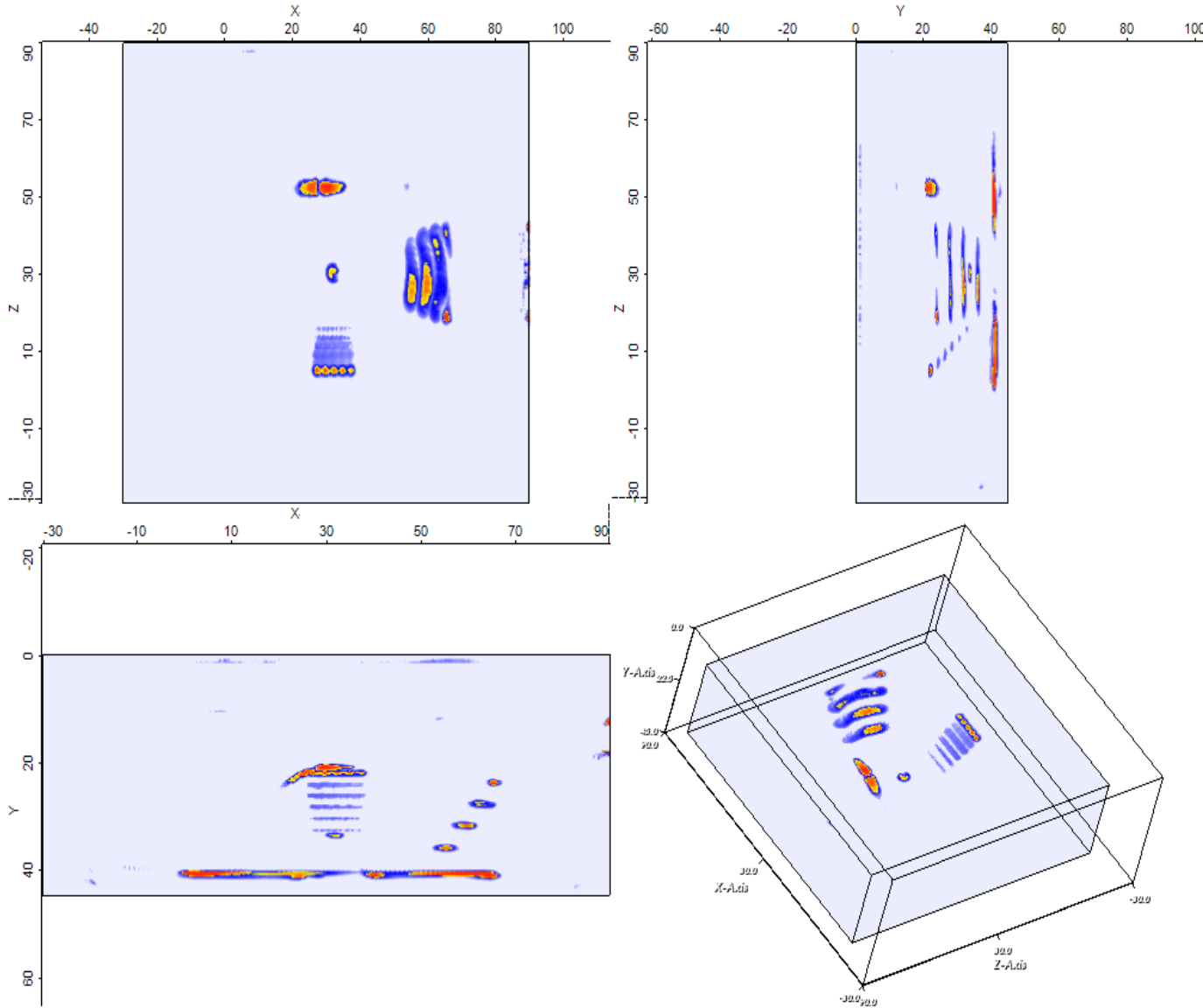
General Research Institute for Nonferrous Metals

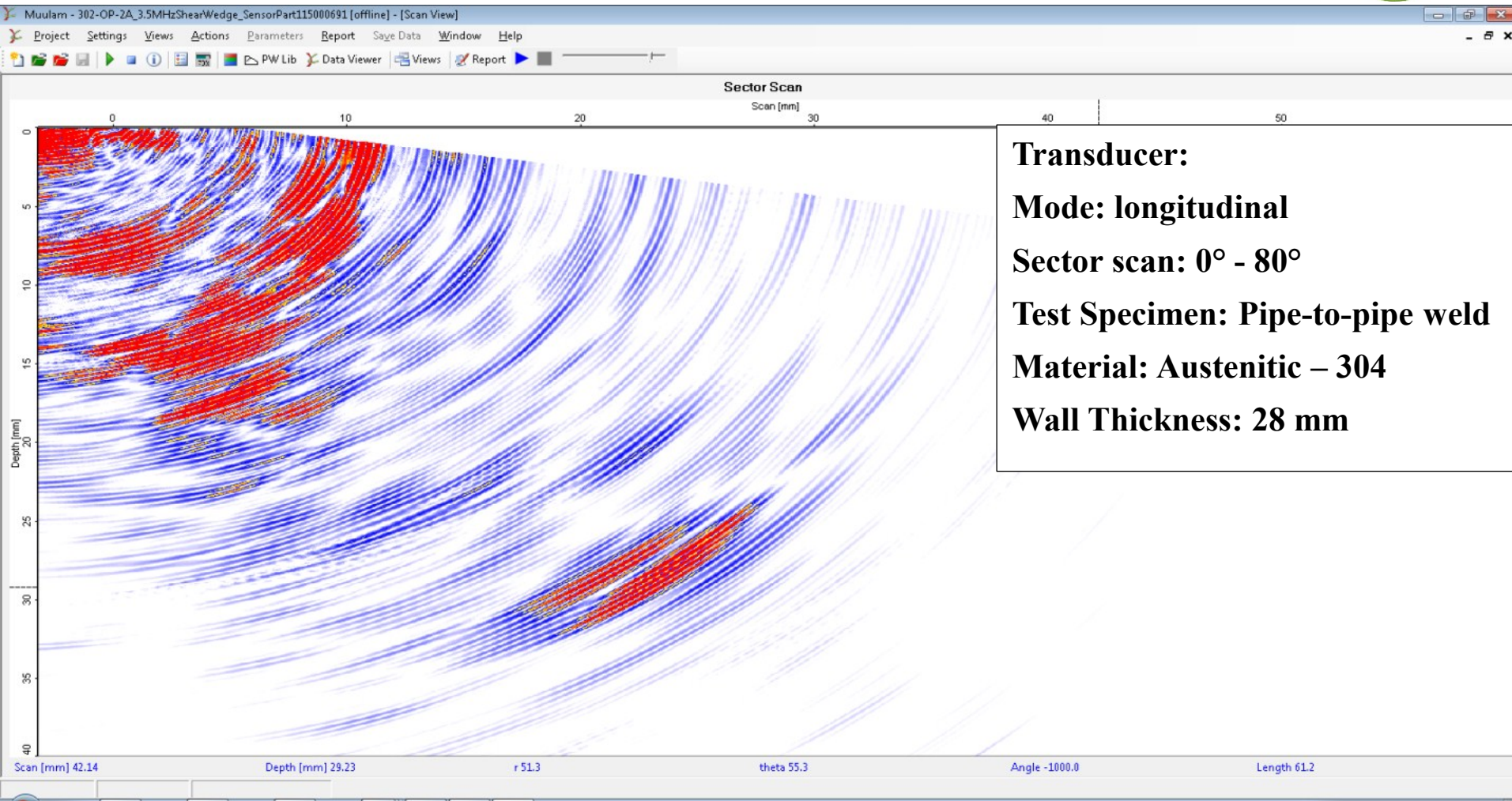
SEMINAR

R&D Laboratory on Industrial Demand



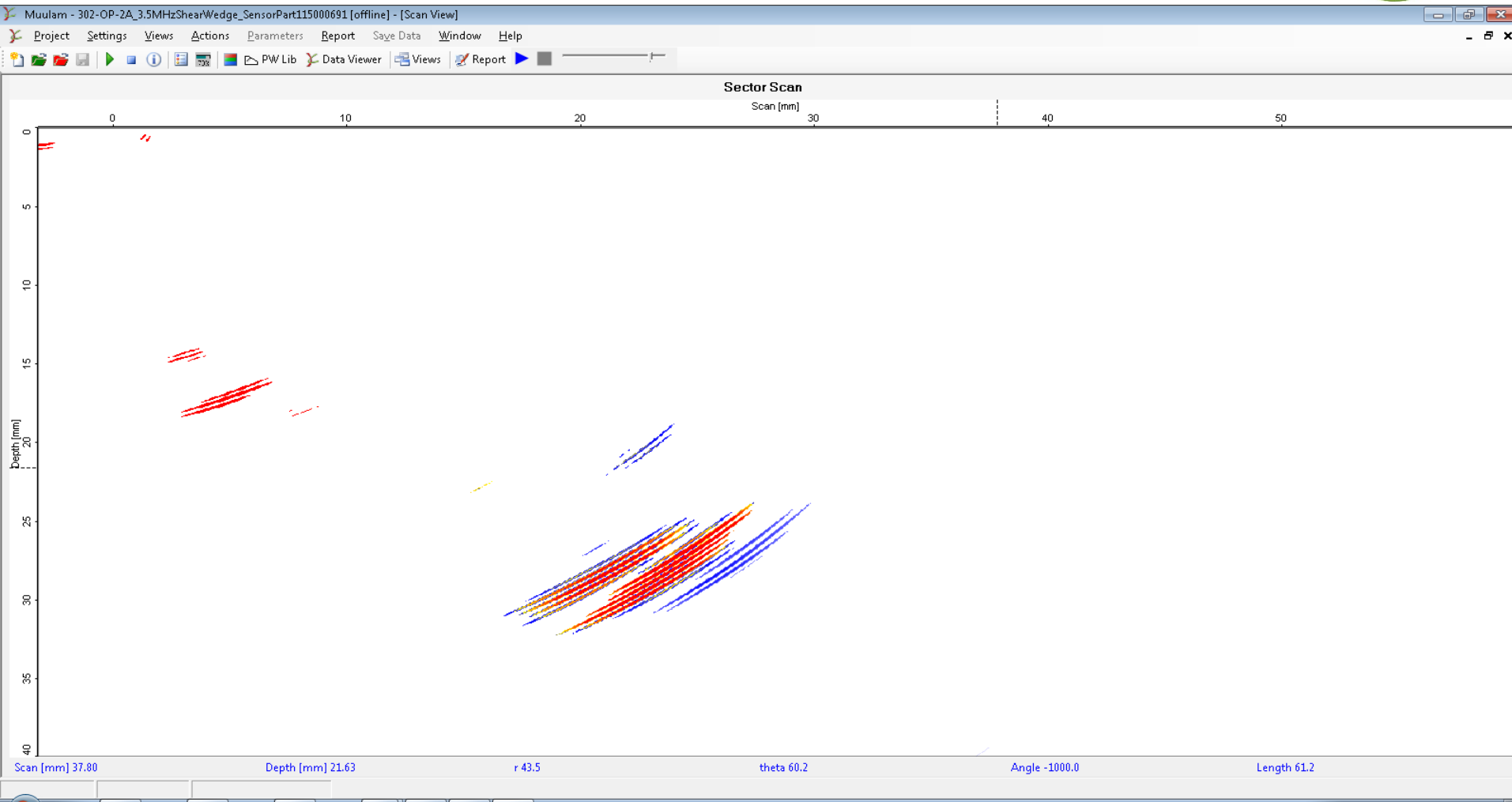
Advanced UT Systems





ACOUSTIC NOISE FILTER

Advanced UT Systems



ACOUSTIC NOISE FILTER

Advanced UT Systems

GRINM

General Research Institute for Nonferrous Metals

SEMINAR

R&D Laboratory on Industrial Demand



THANK YOU
For
YOUR ATTENTION

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Day 2:	Organization and Networks	Speaker
9.00	Welcome Address with Minutes of Last Day	NN
9.30	Recommended Laboratory Structure of Activities	Kröning
10.00	Human Resources – Ethics, Responsibilities, Education, Training and Certification	Klimenov
10.30	Coffee Break	
11.00	Methods I - ET, MT, PT, TT, VT	Vavilov
11.30	X-ray, Betatron	Klimenov
12.00	UT, μ -NDT, NDT Systems	Kröning
12.30	Open Round Discussion (Questions)	all
13.00	Lunch Break	
14.00	Applied Technologies and Capability Networks	Kröning
14.30	Knowledge Strategies and Education	Klimenov
15.00	Coffee Break	
15.30	Added Value Chain in Applied Science	Vavilov
16.00	R&D Driven by Demand – a Project Analysis	Kröning
16.30	Concluding Minutes	to be appointed
17.00	End of Second Day	

<u>Day 3:</u>	CASE STUDIES & NEXT STEPS	Speaker
9.00	Welcome Address with Minutes of Last Day	NN
9.30	Case Studies: Betatron for NDT	Klimenov
10.00	Advanced UT and New Instruments	Kröning
10.30	Coffee Break	
11.00	Thermography for Surface Characterization	Vavilov
11.30	NDT System for In-line NDT	Kröning
12.00	International Cooperation Practice	Klimenov
12.30	Open Round Discussion (Questions)	all NN
13.00	Lunch Break	
14.00	Next Steps and Seminar Evaluation	
16.00	End of Third Day	